IEEE Power Engineering Society
Switchgear Committee
Low Voltage Switchgear Devices Subcommittee

C37.13 and C37.27 Working Group Report October 14, 2008 – Calgary, Alberta, CA

### **Attendance**

- PC37.13 working group met for the Tuesday, October 14, 2008 afternoon session from 2:00 PM to 3:30 PM with 10 present (3 members and 7 guest).
- PC37.27 had no activities as this document previously completed balloting.

Note: Attendance is tracking using AMS system.

#### **Patent Slides**

Mistake made by WG Chair – Patent slides were not shown. By review of Chair, no patent issues arose during the discussion and all participants in the meeting had participated in previous meetings where the IEEE Patent Slides were shown and reviewed.

### C37.13 Recirculation Ballot #2 Results (Draft D23)

PC37.13 Standard for Low-Voltage AC Power Circuit Breakers Used in Enclosures

Recirculation #2 Recirculation #1 Initial Ballot Ballot Open Date: 22-Sep-2008 Ballot Close Date: 07-Oct-2008 RESPONSE RATE This ballot has met the 75% returned ballot requirement. 77 eligible people in this ballot group. 61 affirmative votes 1 negative votes with comments O negative votes without comments 3 abstention votes 65 votes received = 84% returned 4% abstention APPROVAL RATE The 75% affirmation requirement is being met. 61 affirmative votes 1 negative votes with comments 62 votes = 98% affirmative

## Review of Recirculation Ballot #2 (Draft D23) Comments

- WG updated the Resolution comment responses.
- Document is ready for submittal to IEEE with coordination of the update of D23 for editorial changes requested.

### **Future Activities for C37.13**

- The WG does not see need for further action (or immediate revisions). WG should be disbanded upon successful publication.
- -30 C versus -5C Ambient Discussed the resolution to go back to original text of -5C ambient temperature around the circuit breaker. For future revision, the issue of -30 C ambient outside the enclosure (as required by C37.20.1) but with the addition of heaters (or other means) is a consideration.
- Short-Circuit Multiplication Factors for various X/R ratios and for Short-Circuit Testing The document is setup based on the 60 Hz Multiplication Factors and for ratings for Short-Circuit testing. A note was added, "The factors in Table 4 Selection of Multiplier Factors are based on the power frequency of 60 Hz. For 50 Hz circuits, the values in Table 4 can be used, but are conservative."

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Role	Participation Status	First Name	Last Name	Email	Company	10/14/2008
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Member	Active	Т	Olsen	t.olsen@ieee.org	Siemens Power Transmission & Distribution, Inc.	
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Guest	Active	Harry	Josten	harry.josten@ieee.org	Siemens Energy & Automation	
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